

10/570645

IAP6-Rec'd PCT/PTO 03 MAR 2006

5005.1109

UNITED STATES PATENT & TRADEMARK OFFICE

Re: Application of: **Hilmar GUGEL**
Serial No.: To Be Assigned
Filed: Herewith as national phase of International
Application No. PCT/EP2004/051877, filed 23 August
2004
For: **RASTER MICROSCOPE**
Customer No.: 23280

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

March 1, 2006

S i r:

In accordance with the provisions of 37 C.F.R. § 1.97, Applicant hereby makes of record the documents listed on the accompanying PTO-1449 Form (1 page) for consideration by the Examiner in connection with the examination of the above-identified patent application. While the references are being submitted herewith, some or all of the references may not constitute prior art under the U.S. patent laws.

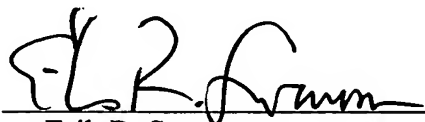
This Information Disclosure Statement is filed under 37 C.F.R. §1.97 (b), before the mailing date of a First Office Action, therefore no fee is believed due. In the event any additional fee is due in connection with this response or if any fee has been overpaid, the deficiency or overpayment should be charged to our Deposit Account No. 50-0552.

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It is respectfully requested that the references cited in the accompanying PTO-1449 form be considered and made of record. It is respectfully submitted that the pending claims are patentable over all of the references made of record at this time.

Respectfully submitted,
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FORM PTO-1449
(REV. 7-80)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY DOCKET NO.

5005.1109

APPLICATION NO.

To be assigned

LIST OF PRIOR ART CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT

Hilmar GUGEL

FILING DATE

Herewith

GROUP

To be assigned

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE IF APPROPRIATE
	A01	6,667,830	Dec. 23, 2003	Iketaki et al.	359	368	
	A02	2002/0167724	Nov. 14, 2002	Iketaki et al.	359	385	
	A03	5,731,588	Mar. 24, 1998	Hell et al.	250	458.1	
	A04	3,437,395	Apr. 8, 1969	H.E. Rosenberger et al.	350	9	
	A05	2002/0109913	Aug. 15, 2002	Gugel et al.	359	387	
	A06	6,555,826	Apr. 29, 2003	Hoffmann	250	458.1	
	A07						
	A08						
	A09						
	A10						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION	
							YES	NO
	A11	DE 44 16 558	Aug. 3, 1995	DE-Germany			Corresponds to US 5,731,588	
	A12	DE 100 12 462	Sep. 20, 2001	DE-Germany			Corresponds to US 6,555,826	
	A13	EP 0 491 289	Jun. 24, 1992	EP-Europe			Discussed in paragraph 10 of specification; see abstract	
	A14							

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	A15	Int. Search Report for Int. Application Serial No. PCT/EP2004/051877 (3 pages)
	A16	M. DYBA et al.: "Focal Spots of Size Lambda/23 Open Far-Field Fluorescence Microscopy at 33nm Axial Resolution", Physical Review Letters, Vol. 88, No. 16, Apr. 22, 2002, pp. 163901-1-163901-4
	A17	T.A. KLAR et al.: Breaking Abbe's Diffraction Resolution Limit in Fluorescence Microscopy with Stimulated Emission Depletion Beams of Various Shapes", Physical Review E, Vol. 64, No. 066613, Nov. 26, 2001, pp. 066613-1-066613-9
	A18	V. Westphal et al.: "Laser-Diode-Stimulated Emission Depletion Microscopy", Applied Physics Letters, Vol. 82, No. 18, 5 May 2003, pp. 3125-3127
	A19	T.A. Klar et al.: "Fluorescence Microscopy with Diffraction Resolution Barrier Broken by Stimulated Emission", Proc. Natl. Acad. Sci. U.S.A., Vol. 97, No. 15, 18 July 2000, pp. 8206-8210
	A20	

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.